

4/23/2015



RELIABILITY MONITOR REPORT  
FOR

**MFN Complementary BiCMOS (CB50)**

**MAXIM INTEGRATED**

160 RIO ROBLES  
SAN JOSE, CA 95134

This Report was prepared by  
**MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3646ETG+
-------------

The calculated failure rate for devices using this process is:

**FAILURE RATE:    MTTF (YRS): 15503    QUANTITY: 160    FAILS: 0    FITS: 7.4**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25    °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2014 and 3/31/2015 .

**Process Information:**

Process Description:            MFN Complementary BiCMOS (CB50)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1347	MAX3646ETG+	135°C	500 HRS	80	0	JJR0J2167UA
HIGH TEMP OP LIFE	1348	MAX3646ETG+	135°C	500 HRS	80	0	JJR0J2168AA
<b>Total:</b>						<b>0</b>	

**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1411	MAX3646ETG+	-65C TO +150C (Condition C)	1000 CYS	79	0	JJR0J2171A
<b>Total:</b>						<b>0</b>	

**TEMPERATURE HUMIDITY BIAS**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1411	MAX3646ETG+	130C, 85% R.H.	100 HRS	80	0	JJR0J2171A
<b>Total:</b>						<b>0</b>	

**FAILURE RATE:    MTTF (YRS): 15503    QUANTITY: 160    FAILS: 0    FITS: 7.4**